

**Search Notes**

Application/Control No.

10/717,364

Examiner

Edwin C. Holloway, III

Applicant(s)/Patent under  
Reexamination

CHANG, APIN

Art Unit

2635

**SEARCHED**

Class	Subclass	Date	Examiner
341	176 175	6/26/2005	EH
340	5.64 5.71		
340	5.72		
340	825.69		
340	825.72		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST search notes attached	6/26/2005	EH